

| L Number | Hits | Search Text | DB | Time stamp |
|----------|------|---|---|------------------|
| 85 | 76 | distance with (template and (substrate or wafer)) | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/04/13 14:15 |
| 86 | 550 | pattern\$2 near template and (substrate or wafer) | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/04/13 14:43 |
| 88 | 16 | gap with (pattern\$2 near template and (substrate or wafer)) | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/04/13 14:44 |
| 89 | 33 | determin\$3 with (pattern\$2 near template and (substrate or wafer)) | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/04/13 14:45 |
| 90 | 86 | (pattern\$2 near template and (substrate or wafer)) and distance and gap | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/04/13 14:45 |
| 91 | 18 | ((pattern\$2 near template and (substrate or wafer)) and distance and gap) and light near reflect\$3 | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/04/13 14:45 |
| 92 | 84 | gap with (template and (substrate or wafer)) | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/04/13 14:46 |
| 93 | 84 | gap with (template and (substrate or wafer)) | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/04/13 14:46 |
| 87 | 44 | (measur\$3 or determin\$4) with (pattern\$2 near template and (substrate or wafer)) | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/04/13 14:46 |